# EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| S1 | 681 | (702/179).CCLS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/03/13 09:50 |
| S2 | 153 | (702/109,110).CCLS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/03/13 09:50 |
| S3 | 1760 | (702/57,58,117).CCLS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/03/13 09:50 |
| S4 | 426 | (324/716,718).CCLS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/03/13 09:50 |
| S5 | 0 | (model$1base$1 near monitor$3) and (goodness near1 fit$1) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 09:51 |
| S6 | 4 | ((manipulat$5 calculat$5 form$3) with (goodness near1 (fit$3 measur$4 statistical$3))) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
| S7 | 0 | ((manipulat$5 calculat$5 form$3) with (goodness near1 (fit$3 measur$4 statistical$3))) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) and (independent with variable$1) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
| S8 | 0 | (((manipulat$5 calculat$5 form$3) with (goodness near1 (fit$3 measur$4 statistical$3))) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) and (independent with variable$1)).clm. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
| S9 | 681 | S1 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |

| S10 | 0 | S4 and S1 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
|---|---|---|---|---|---|---|
| S11 | 0 | S2 and S4 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
| S12 | 2 | S4 and S3 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:32 |
| S14 | 0 | S12 and S6 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:10 |
| S15 | 0 | S6 and S1 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:11 |
| S16 | 0 | S2 and S6 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:11 |
| S17 | 0 | S3 and S6 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:11 |
| S18 | 0 | S4 and S6 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:11 |
| S19 | 1 | "20050027476" | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:49 |
| S20 | 0 | ((goodness with fit$1) with value$1) same (independent with variable$1) same ((measur$4 actual) near1 value$1) same (process$3 near control$1) same (form$3 with (device$1 structure$1)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:51 |
| S21 | 1 | (monitor$3 with (process$3 near stability)) and (fit$3 with value$1) and (linear$3 with regression$3) and (coefficient$1 near (relat$3 correlat$3)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 10:53 |

# EAST Search History

| S22 | 1 | (monitor$3 with (process$3 defect$1 device$1 structure$1 wafer$1) ) and ((us$3 usag$3) with (goodness near (curve$1 fit$1) near value$1) ) and (process$3 with control$3 with (limit$1 threshold$1)) and (independent$1 with variable$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:56 |
|-----|---|---|---|---|---|---|
| S23 | 0 | ((monitor$3 with (process$3 defect$1 device$1 structure$1 wafer$1) ) and ((us$3 usag$3) with (goodness near (curve$1 fit$1) near value$1) ) and (process$3 with control$3 with (limit$1 threshold$1)) and (independent$1 with variable$1)).clm. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |
| S24 | 0 | ((statisticS3 near analys$3) and (goodness near (curve$1 fitS4) ) ) same (process$3 adj control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:01 |
| S25 | 0 | ((statisticS3 near analys$3) and (goodness near (curve$1 fitS4) ) ) same (process$3 adj control$3) same ((calculat$4 manipulat$4) with (goodness near2 value$1)) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |
| S26 | 0 | S25 and S1 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |
| S27 | 0 | S25 and S2 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |
| S28 | 0 | S25 and S3 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |
| S29 | 0 | S25 and S4 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:57 |

| S30 | 0 | ((monitor$3 with (process$3 defect$1 device$1 structure$1 wafer$1) ) same ((us$3 usag$3) with (goodness near (curve$1 fit$1) near value$1) ) same (process$3 with control$3 with (limit$1 threshold$1)) same (independent$1 with variable$1)).clm. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 10:58 |
|---|---|---|---|---|---|---|
| S31 | 0 | ((monitor$3 with (process$3 defect$1 device$1 structure$1 wafer$1) ) same ((us$3 usag$3) with (goodness near (curve$1 fit$1) near value$1) ) same (process$3 with control$3 with (limit$1 threshold$1)) same (devi$5 with sheet with resist$4) same (independent$1 with variable$1)).clm. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:00 |
| S32 | 0 | S31 and S1 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:00 |
| S33 | 0 | S31 and S2 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:00 |
| S34 | 0 | S31 and S3 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:00 |
| S35 | 0 | S31 and S4 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:00 |
| S36 | 0 | S31 and S6 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:01 |
| S37 | 0 | (((manipulat$3 calculat$3 formS3)with (goodness nearl (fitS3 measur$4 statistical$3)) ) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) )and ((statisticS3 near analys$3) and (goodness near (curve$1 fitS4) ) ) same (process$3 adj control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:02 |

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|---|---|---|---|---|---|---|
| S38 | 0 | (((manipulat$3 calculat$3 form$3)with (goodness nearl (fitS3 measur$4 statistical$3)) ) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) )and ((statisticS3 near analys$3) and (goodness near (curve$1 fitS4) ) ) same (process$3 adj control$3) same (monitor$3 with (sheet$1 with resist$4)) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:02 |
| S39 | 0 | (((manipulat$3 calculat$3 form$3)with (goodness nearl (fitS3 measur$4 statistical$3)) ) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) )and ((statistic$3 near analys$3) and (goodness near (curve$1 fit$4) )near value$1 ) same (process$3 adj control$3) same (monitor$3 with (sheet$1 with resist$4)) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:04 |
| S40 | 0 | ((((manipulat$3 calculat$3 form$3)with (goodness nearl (fitS3 measur$4 statistical$3)) ) and ((semiconductor$1 wafer$1) with (form$3 near process$3)) )and ((statistic$3 near analys$3) and (goodness near (curve$1 fit$4) )near value$1 ) same (process$3 adj control$3) same (monitor$3 with (sheet$1 with resist$4))).clm. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:06 |
| S41 | 784 | (700/109,110).CCLS. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/03/13 11:06 |
| S42 | 1 | ((curve near fit$3) near value$1) and (screen$3 with (device$1 structure$1)) and (defect$1 with detect$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:08 |
| S43 | 23 | (curve near fitt$3) and (process$3 with (controL$3 monitor$3)) and (detect$3 with defect$1) and (goodness near fit$4) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/10/29 11:28 |

| S44 | 1 | S43 and S1 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:08 |
|---|---|---|---|---|---|---|
| S45 | 0 | S44 and S2 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:08 |
| S47 | 0 | S41 and S43 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:09 |
| S48 | 0 | (curve near fitt$3) and (process$3 with (controL$3 monitor$3)) and (detectS3 with defect$1) and ((goodness nearl (fit$4 measur$3)) (coefficient$1near correlation$1)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:09 |
| S50 | 46 | (curve near fitt$3) and (process$3 with (control$3 monitor$3)) and (detect$3 with defect$1) and ((goodness nearl (fit$4 measur$3)) (coefficient$1 near correlation$1)) and (sheet$1 near (resistance resistivity)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/26 16:27 |
| S51 | 1 | S50 and S1 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:11 |
| S52 | 0 | S50 and S41 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:11 |
| S54 | 1 | S50 and S43 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:11 |
| S55 | 0 | S50 and S23 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/13 11:12 |

| S57 | 0 | (curve near fitt$3) and (process$3 With (control$3 monitor$3)) and (detect$3 with defect$1) and ((goodness near1 (fit$4 measur$3)) (coefficient$1 near correlation$1)) and (test$3 with (structure$1 wafer$1)) and (model$1 base$1 with statistic$3) and (form$3 near (device$1 structur$3)) and ((divid$3 divis$3) with (parameter$1 near sheet$1 near resist$4)) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:17 |
|---|---|---|---|---|---|---|
| S58 | 0 | ( (curve near fitt$3) and (process$3 With (control$3 monitor$3)) and (detect$3 with defect$1) and ((goodness near1 (fit$4 measur$3)) (coefficient$1 near correlation$1)) and (test$3 with (structure$1 wafer$1)) and (model$1 base$1 with statistic$3) and (form$3 near (device$1 structur$3)) and ((divid$3 divis$3) with (parameter$1 near sheet$1 near resist$4)) and (test$1 near (condition$1 environment$1))). clm. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:18 |
| S60 | 0 | S58 and S1 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:18 |
| S61 | 0 | S58 and S2 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:19 |
| S62 | 335 | (702/118).CCLS. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/03/13 11:21 |
| S63 | 0 | S6 and S62 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:21 |
| S64 | 0 | S62 and S58 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/13 11:21 |

| S65 | 2 | (("5574890") or ("6403389")).PN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/03/14 11:40 |
|---|---|---|---|---|---|---|
| S66 | 1 | S65 and monitor$3 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:41 |
| S67 | 2 | S65 and (monitor$3 control$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:41 |
| S68 | 28 | ("3335340" | "3974443" | "4445180" | "4516071" | "4560583" | "4722154" | "4871962" | "4972248" | "5010029" | "5561373" | "5719495" | "5793471" | "5854097" | "5857258" | "5883437" | "5933020" | "5963784" | "6019850" | "6022750" | "6028440" | "6087189" | "6291254").PN. OR ("6403389").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:46 |
| S69 | 0 | (process$3 near control$3 and monitor$3) same (wafer$1 semiconductor$1) same (best near fit$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:47 |
| S70 | 21 | (curve near fitt$3) and (process$3 With (control$3 monitor$3)) and (detect$3 with defect$1) and ((goodness near1 (fit$4 measur$3)) (coefficient$1 near correlation$1)) and (test$3 with (structure$1 wafer$1)) and (model$1 base$1 with statistic$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:47 |
| S71 | 591 | (process$3 near control$3 and monitor$3) and (wafer$1 semiconductor$1) and (best near fit$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:48 |
| S72 | 5 | (process$3 near control$3 and monitor$3) and (wafer$1 semiconductor$1) and (best near fit$3) and (GOF$1) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/03/14 11:51 |

| S73 | 18988 | (GOF$1 (best$1fit$3) (goodness with fit$3)) and (monitor$3 control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/14 11:52 |
|---|---|---|---|---|---|---|
| S74 | 508 | (GOF$1 (best$1fit$3) (goodness with fit$3)) with (monitor$3 control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/14 11:52 |
| S75 | 241 | ((GOF$1 (best$1fit$3) (goodness with fit$3)) with (monitor$3 control$3) ) and (measur$4 and device$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/14 11:53 |
| S76 | 19 | ((GOF$1 (best$1fit$3) (goodness with fit$3)) with (monitor$3 control$3) ) same (measur$4 and device$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/14 11:54 |
| S77 | 215178 | ((goodness near fit$3) (curve near fitt$3) (fitt$3 nearl goodness) (foodness near2 measur$4)) same ((control$3 near limit$1) (threshold nearl controL$3) (control$3 near threshold) (limit$3 near value$1)) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/14 11:54 |
| S79 | 1 | "20050027476" | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:09 |
| S80 | 1 | S79 and (test$1 near site$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:17 |
| S81 | 1 | (linear with fit$3 with regression$3) and (test$1 with site$1) and wafer and (process$3 near control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:18 |
| S82 | 25 | (linear with fit$3 with regression$3) and (test$1 with site$1) and (process$3 near control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:20 |
| S83 | 4 | (("6.403,389") or ("5,627,101") or ("5.987,398") or ("5,883.437") or ("6.466,038") or ("5,514,974") or ("6,087,189") or ("5,552, 718")).PN. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/03/15 15:20 |

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| S84 | 8 | (("6403389") or ("5627101") or ("5987398") or ("5883437") or ("6466038") or ("5514974") or ("6087189") or ("5552718")).PN. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/03/15 15:21 |
|---|---|---|---|---|---|---|
| S85 | 28 | ("3335340" \| "3974443" \| "4445180" \| "4516071" \| "4560583" \| "4722154" \| "4871962" \| "4972248" \| "5010029" \| "5561373" \| "5719495" \| "5793471" \| "5854097" \| "5857258" \| "5883437" \| "5933020" \| "5963784" \| "6019850" \| "6022750" \| "6028440" \| "6087189" \| "6291254").PN. OR ("6403389").URPN. | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:32 |
| S86 | 1 | S80 and (device$1 near screen$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:32 |
| S87 | 1 | ("6403389").PN. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/03/15 16:21 |
| S88 | 0 | S87 and (test$1 and site$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:41 |
| S89 | 1 | S87 and structure$1 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:51 |
| S90 | 127 | (wafer$1 near defect$1 )with (screen$3 monitor$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:51 |
| S91 | 0 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) same (fit$3 and curve$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 15:52 |
| S92 | 7 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:53 |
| S93 | 0 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) and (test$1site$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:54 |

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|---|---|---|---|---|---|---|
| S94 | 0 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) and (test with site$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:54 |
| S95 | 0 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) and (ATE) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:54 |
| S96 | 1 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) and (ATE tester$1) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:55 |
| S97 | 1 | ((wafer$1 near defect$1 )with (screen$3 monitor$3) ) and (statistic$3 with process$3 with control$3) and (ATE testers) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:57 |
| S98 | 38 | (wafer$1 with tester$1) same (process$3 with evaluat$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:58 |
| S99 | 0 | (wafer$1 with tester$1) same (process$3 with evaluat$3) same (statistic$3 with (fit$3 GOF best$1fit$3) ) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 17:58 |
| S10 0 | 18 | (wafer$1 with tester$1) same (process$3 with evaluat$3) same screen$3 | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/03/15 18:00 |
| S10 1 | 8 | (wafer$1 with tester$1) same (process$3 with evaluat$3) same screen$3 and (control$3 with process$3) | US-PGPUB ; USPAT; USOCR | OR | ON | 2007/10/29 11:27 |
| S10 2 | 1 | ("6217651").PN. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/10/26 16:25 |
| S10 3 | 2118 | (702/109,110,57,58,117).CCLS. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/10/26 16:26 |
| S10 4 | 858 | (700/109,110).CCLS. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/10/26 16:26 |
| S10 5 | 430 | (324/716,718).CCLS. | US-PGPUB ; USPAT; USOCR | OR | OFF | 2007/10/26 16:26 |

| S106 | 47 | (curve near fitt$3) and (process$3 with (control$3 monitor$3)) and (detect$3 with defect$1) and ((goodness nearl (fit$4 measur$3)) (coefficient$1 near correlation$1)) and (sheet$1 near (resistance resistivity)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/26 16:54 |
|---|---|---|---|---|---|---|
| S107 | 1 | S106 and S103 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/26 16:55 |
| S108 | 1 | "20050027476" | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/26 16:56 |
| S109 | 37457 | ("700").CLAS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/10/29 11:12 |
| S110 | 133895 | ("438").CLAS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/10/29 11:12 |
| S111 | 8 | (wafer$1 with tester$1) same (process$3 with evaluat$3) same screen$3 and (control$3 with process$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/29 11:28 |
| S112 | 1 | S111 and (S109 S110) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/29 11:28 |
| S113 | 23 | (curve near fitt$3) and (process$3 with (controL$3 monitor$3)) and (detect$3 with defect$1) and (goodness near fit$4) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/29 11:28 |
| S114 | 0 | S113 and (S109 S110) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/29 11:28 |
| S115 | 0 | ((wafer chuck$1 workpiece$1) with (test$3 near condition$3)) and ((curve$1 near fit$3)) and ((process$3 control$3 monitor$3) with (defect$1)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/29 11:43 |

| S116 | 1 | "20050027476" | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/30 11:56 |
|------|---|---------------|-------------------------|----|-----|------------------|
| S117 | 2596 | (438/14).CCLS. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/10/30 11:57 |
| S118 | 7444 | (wafer$1 chuck$1piece$1 workpiece$1) same (defect$3 with (detect$3 control$3 monitor$3)) | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/30 12:10 |
| S119 | 11378 | ((test$3 near condition$1) with (temperature$1 intensity light$3)) and2 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/30 12:48 |
| S120 | 37 | ((test$3 near condition$1) with (temperature$1 intensity light$3)) and S118 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/30 13:14 |
| S121 | 1 | S117 and S120 | US-PGPUB; USPAT; USOCR | OR | ON | 2007/10/30 13:14 |